

LISTING OF THE CLAIMS

Please amend the Claims as follows:

1. (currently amended) Apparatus for testing an integrated circuit, comprising:

a data source coupled to the integrated circuit to provide test signals to ~~an~~
the integrated circuit being tested;

a plurality of relays selectively ~~connecting~~ coupling the integrated circuit
~~being tested~~ to the apparatus wherein the integrated circuit is tested;

a plurality of fan out elements coupled to receive data pulses from the
plurality of relays and to distribute the data pulses to a plurality of latches; and

a strobe element associated with each ~~latch thereby~~ of the plurality of
latches for enabling each latch of the plurality of latches to transfer the data pulses
from an input port to an output port of each ~~latch~~ of the plurality of latches.

2. (previously presented) The apparatus of claim 1, further comprising testing components of
said apparatus each coupled to the receive the data pulses from one of the plurality of latches,
the testing components of said apparatus receiving the data pulses at a frequency that is a
fraction of the output signal frequency of the integrated circuit being tested.

3. (previously presented) The circuit network of claim 2, wherein the fraction is equal to the
output frequency of the integrated circuit being tested divided by the number of the latches.

4. (currently amended) A method of testing an integrated circuit comprising the acts of:

providing an integrated circuit;

applying signals to an input port of the integrated circuit;

fanning out data pulses received from an output port of the integrated circuit ~~tested~~;
distributing each of the data pulses ~~each~~ to one of a plurality of latches; and
calibrating a time at which each one of the plurality of latches is enabled by a strobe
element.

5. (previously presented) The method of claim 4, further comprising the acts of:

measuring the time between initialization of the integrated circuit and detection of a
first data pulse at an input port of a selected one of the plurality of latches;
calculating a clock frequency of the integrated circuit therefrom, and;
testing the integrated circuit after the measuring and calculating are performed.

6. (previously presented) The method of claim 4, further comprising the act of transmitting a
repetitive bit stream with alternating voltage levels from the integrated circuit to calibrate a
time at which each one of the plurality of latches is enabled.

7. (previously presented) The method of claim 4, further comprising the act of edge
transitions at the output terminal of each one of the plurality of latches thereby to calibrate a
time at which each one of the plurality of latches is enabled.